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450 mm and Nikon Advanced Lithography

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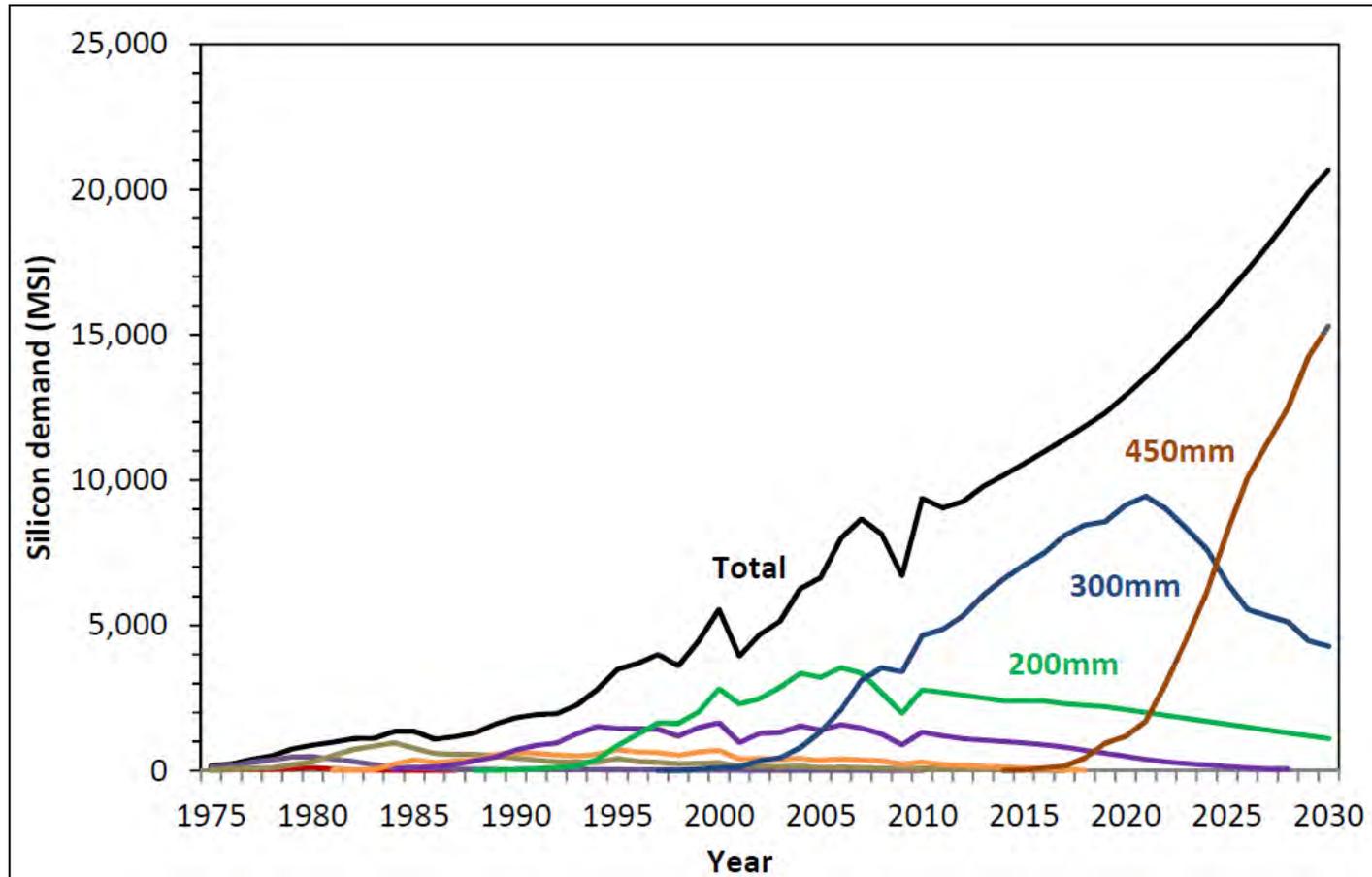
SOKUDO Breakfast 2013

- **Drivers and Current 193 nm Evolutionary Advances**
- **450 nm Economics and Technology**
- **Nikon and 450 nm**

WW Silicon Demand Keeps Growing...



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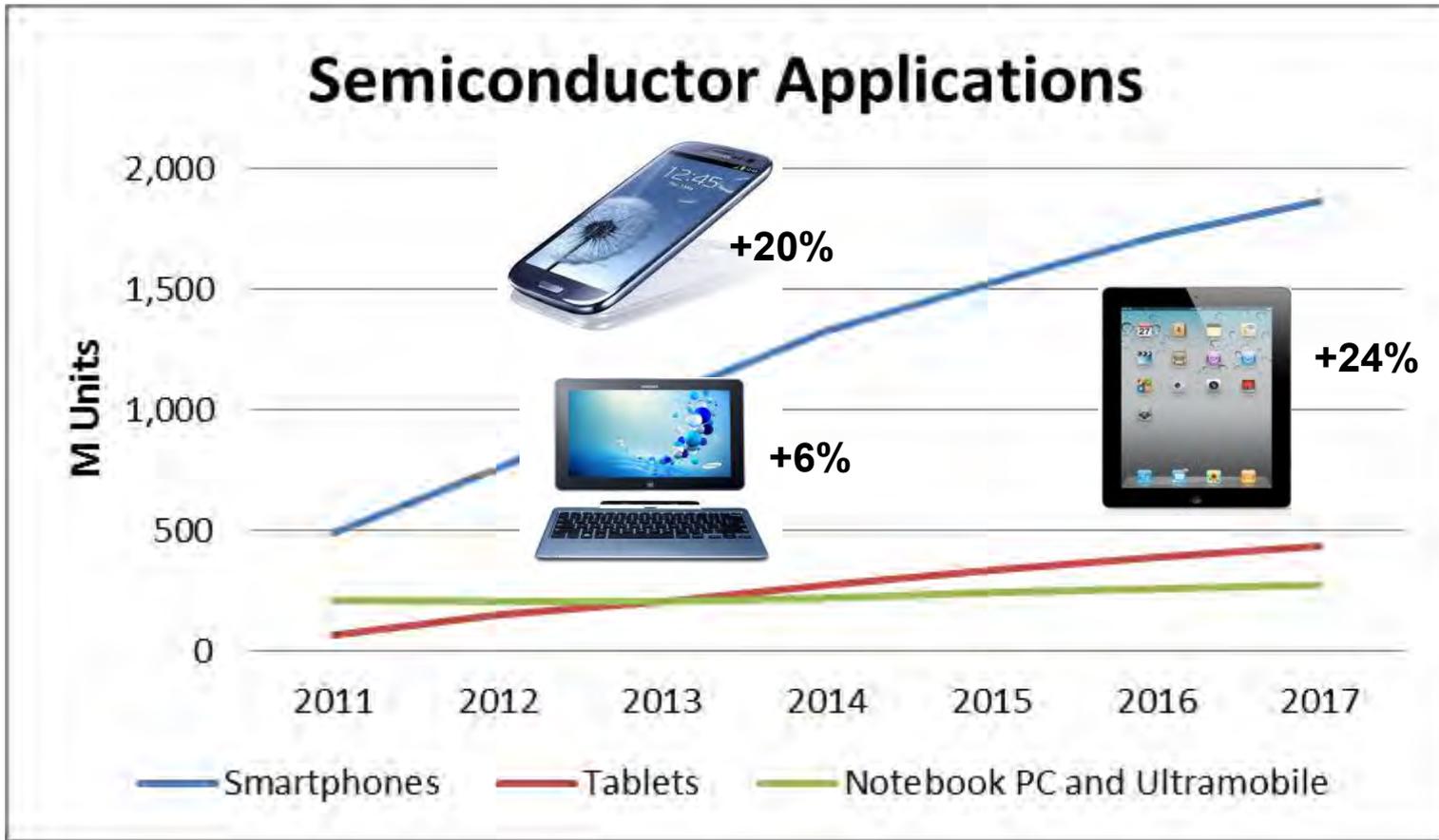
Ref: IC Knowledge 2012

Tremendous projected growth and opportunity

...Fueled by Increasing Applications



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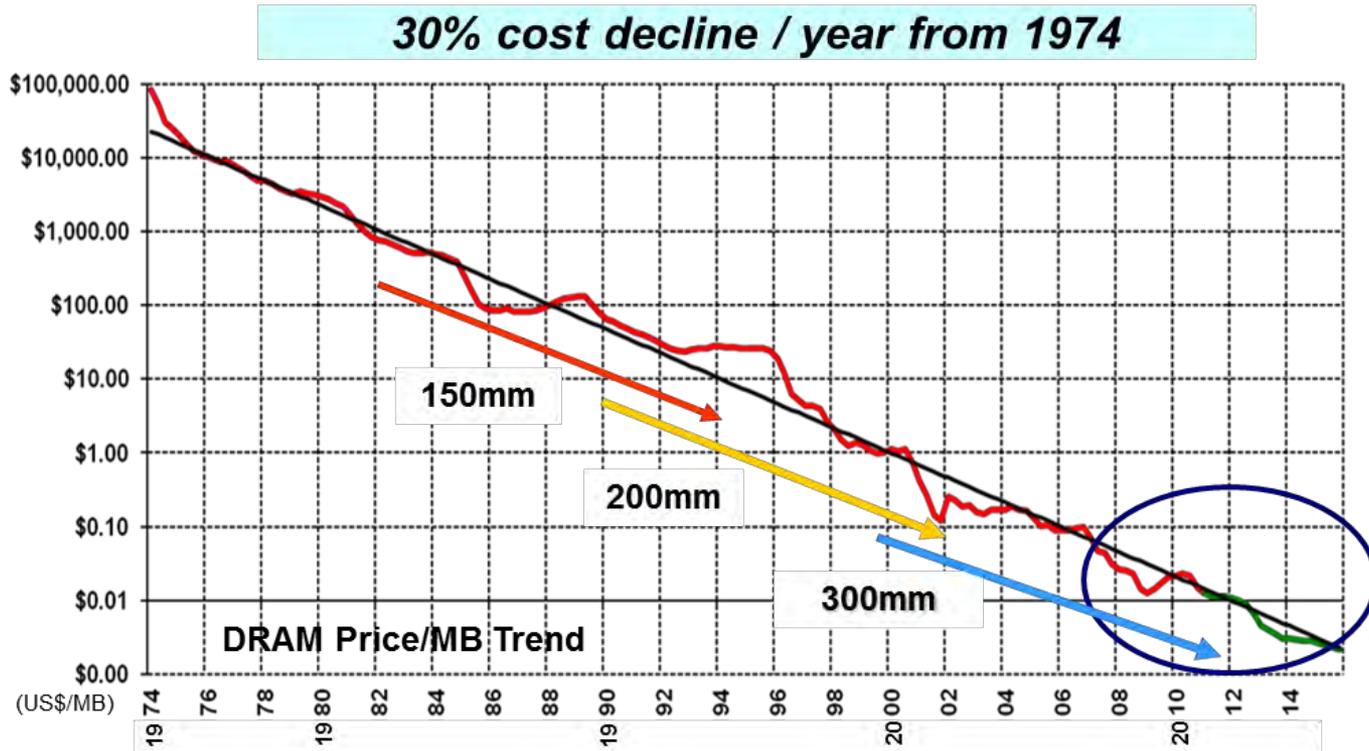
Ref: Gartner Q1'13 – CAGR: 5 years 2012- 2017

Driven by Mobile Applications

450 mm Motivation



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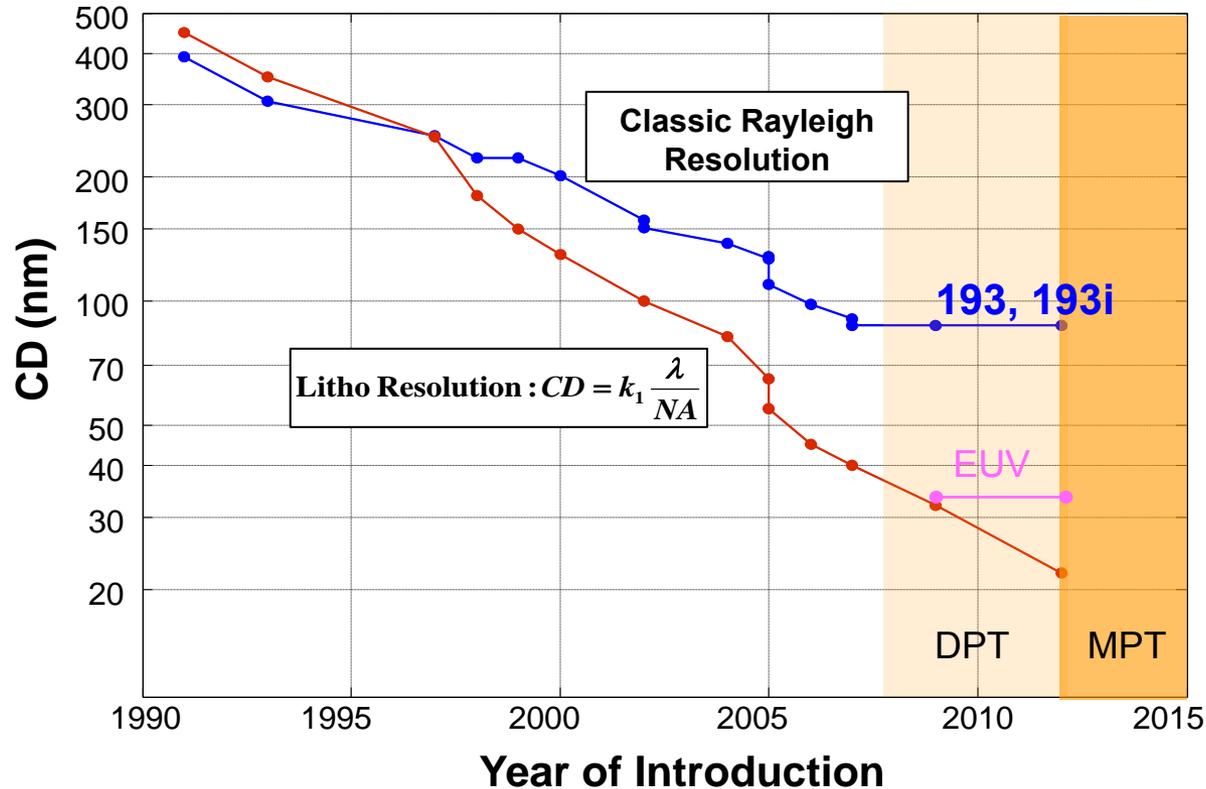
Cost per MB has been a driver for industry success

Lithography Resolution and Complexity



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Resolution vs. Year of Introduction



Resolution comes at the expense of increasing complexity and cost, especially with multiple processing and EUV

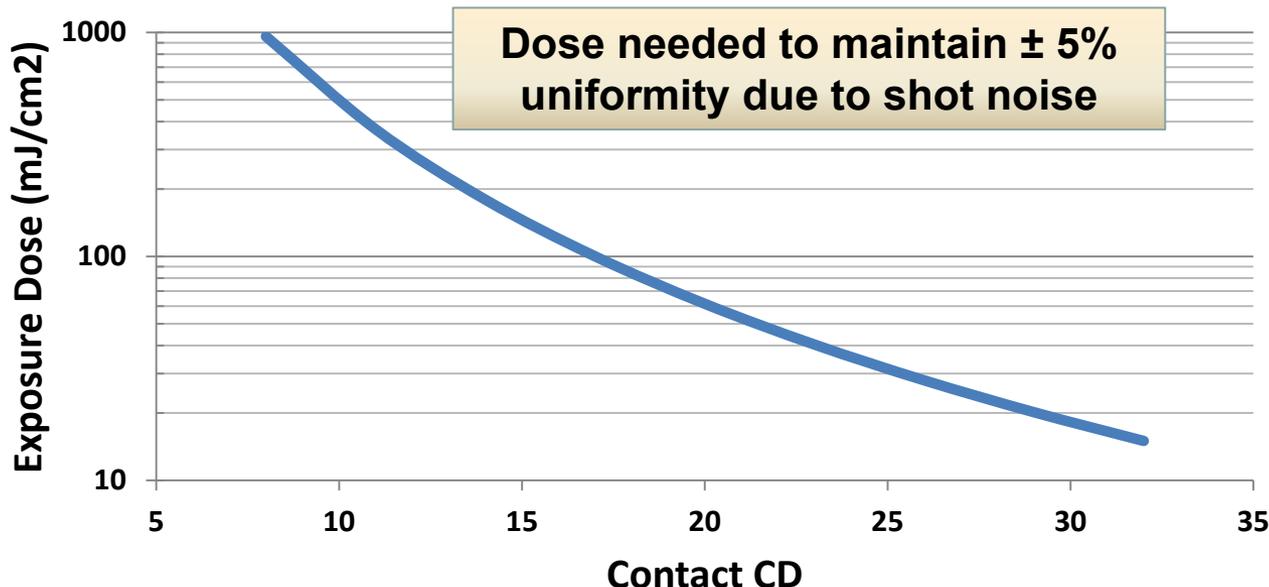
EUV and 193i Extension for HVM



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- **EUV continues to face eco-system issues**

- source power, photoresist and mask complexity continue to plague EUV



- 450 mm and EUV will need >500W at IF for throughput and image quality

- **Extending 193 nm immersion is a proven core technology with an established platform**

- Provides a strong framework for innovation
- Early pilot tooling availability and clear HVM strategy

450 mm litho readiness thru ArF immersion extension

450 mm: Economics and Technology



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Maintaining Moore's Law in a cost-effective way

Wafer Area +2.25X and Effective Chip Area +2.4X

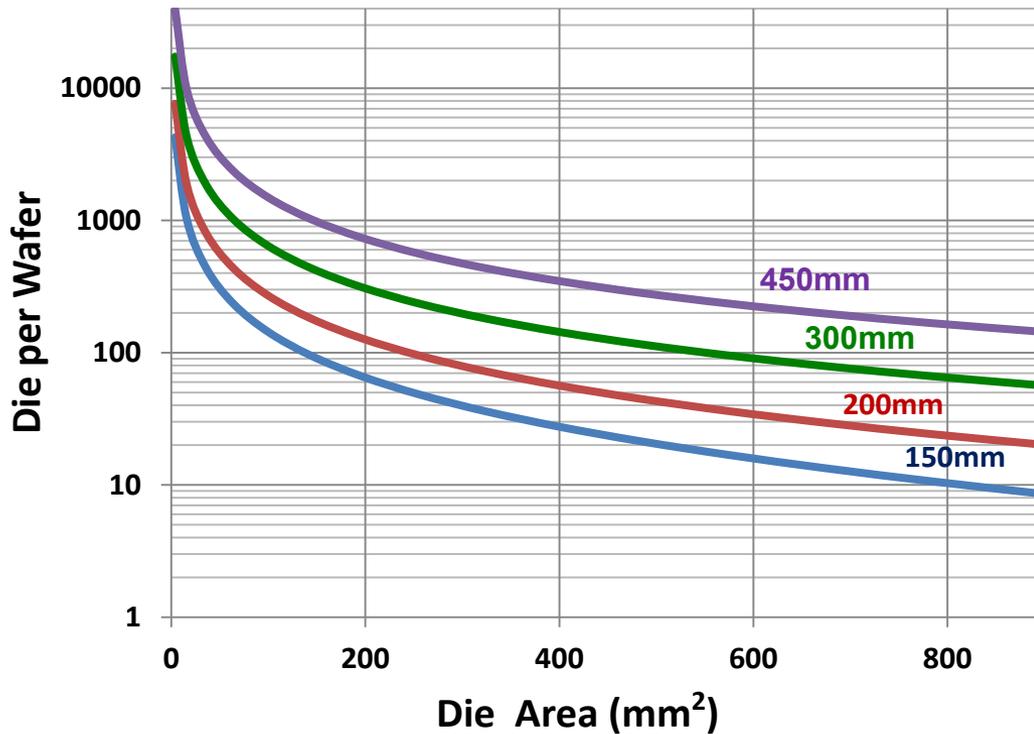
Reduces increase in per unit area process costs associated with the technology evolution

450 mm Die Fundamentals



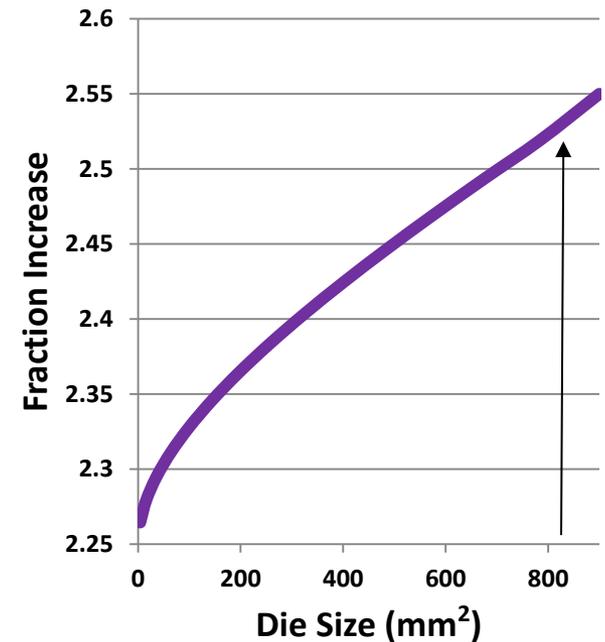
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Die Per Wafer and Wafer Size



~2.4X Gain for Each Generation

Die increase with 450mm



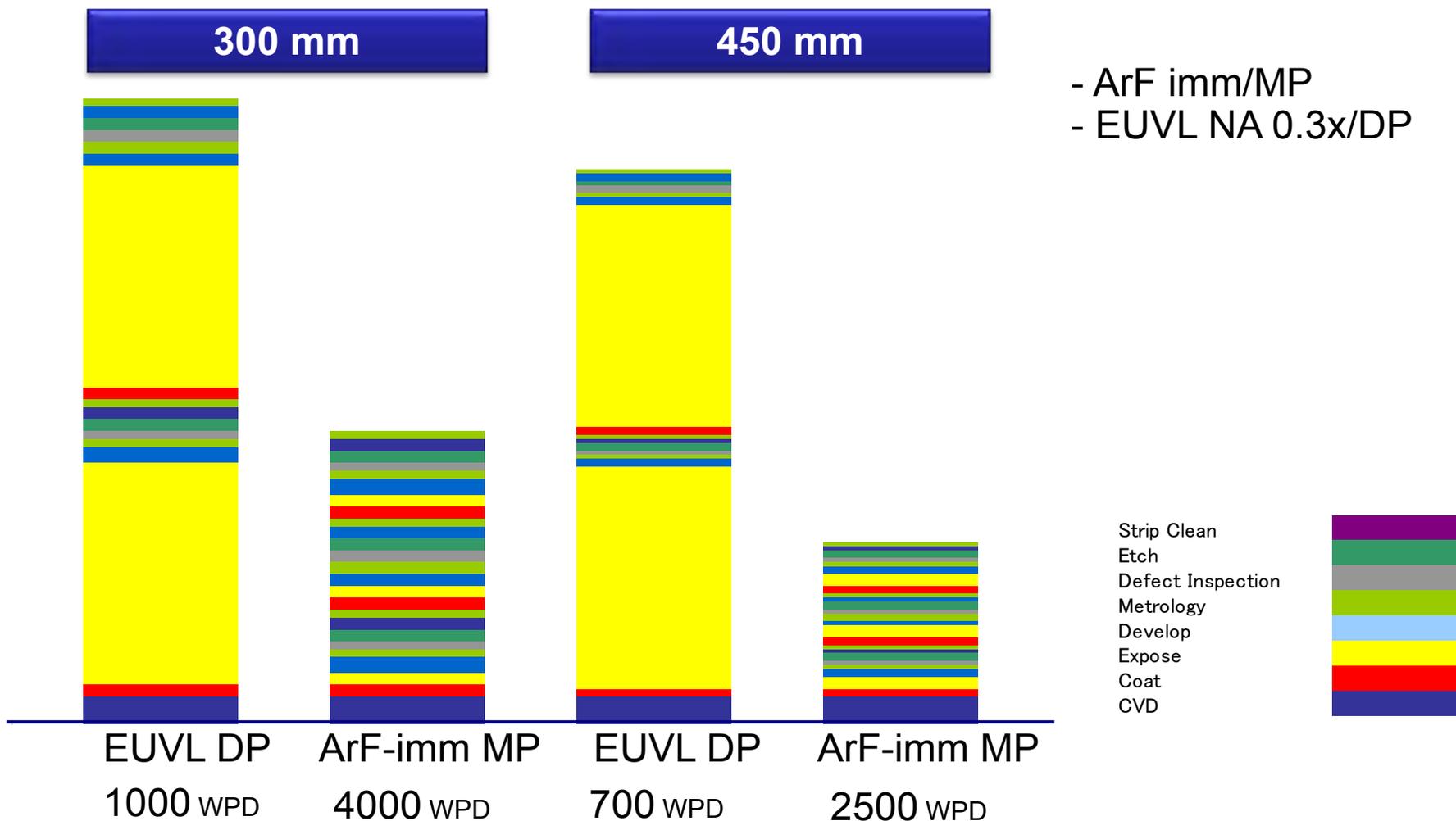
Exact gain will depend on die size and scanner field utilization

Process Step and Cost Comparison



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In case of N10



**450 mm will enable continuation of Moore's law
and further extend 193 nm immersion**

450 mm: Economics and Technology



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Greater Economies of Scale for IC Manufacturing:

Boost property, plant, equipment (PPE) and employee productivity, and reduce associated costs

450 mm: Economics and Technology



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Stimulate Industry Innovation:

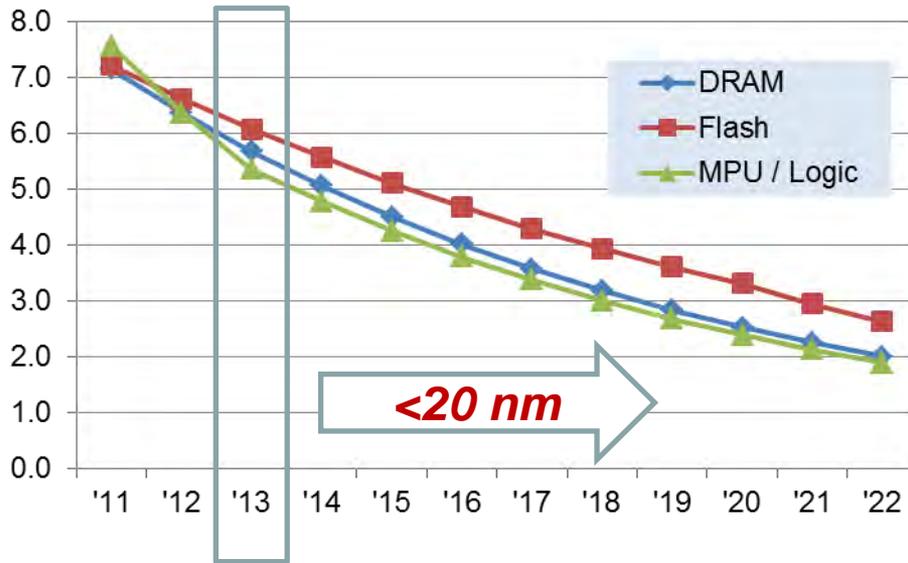
Designers have the chance to think outside of the box

Litho Requirements: CD and Overlay

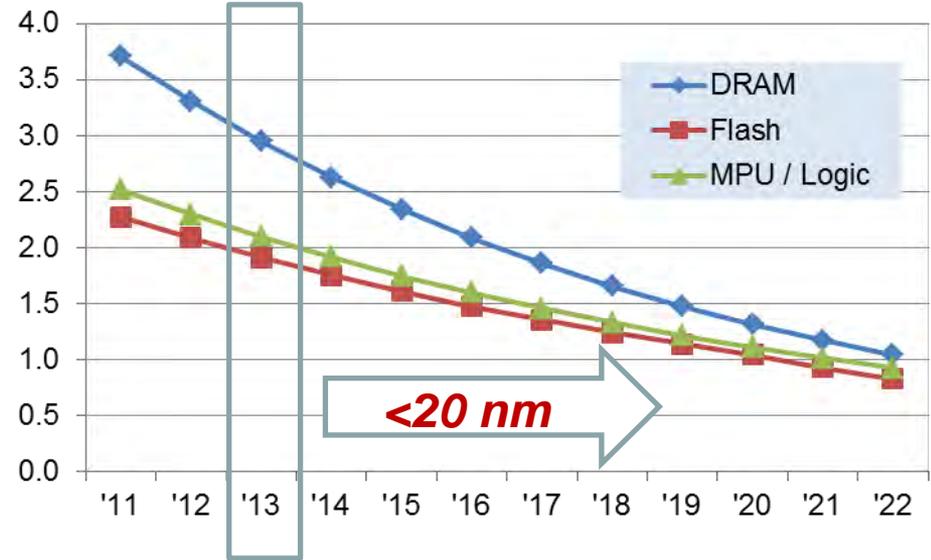


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Mix-Match Overlay



CD Control



On-going improvements to productivity, overlay, and CD control are essential for future scaling and 450 mm

450 mm Challenges



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- **The equipment of the 450 mm generation will have to meet:**
 - Currently unknown high yield manufacturing ramp rates
 - Challenging levels of defect free operation and extreme reliability performance
 - Specifics to Scanners: demanding throughput, overlay and CD specifications
- **A series of research and development efforts will have to be invested into equipment innovation and improvements**
- **Example of a Stage Size Challenge**
 - Let's assume linear scaling (big simplification), then increasing wafer diameter 1.5x means the stage mass is diameter³ ≈ 3.4X, and hence motors need 3.4X greater force, but motor heat scales with force²

Innovation is occurring at Nikon to meet these challenges

450 mm: Economics and Technology



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Many Opportunities for Invention and Expanded Industry Collaboration:

Tooling, automation, IC manufacturing processes, green tech, etc.

450 mm: Cost and Technology Innovation

Nikon 450 mm Machine



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- Large scale corporate program utilizing top worldwide engineering talent to develop and build the 450 mm scanner system
- Nikon leading tools S621/S622D(immersion), and S320F(dry) have high overlay accuracy and throughput
- The proven *Streamalign* Platform provides an effective foundation for the 450 mm system

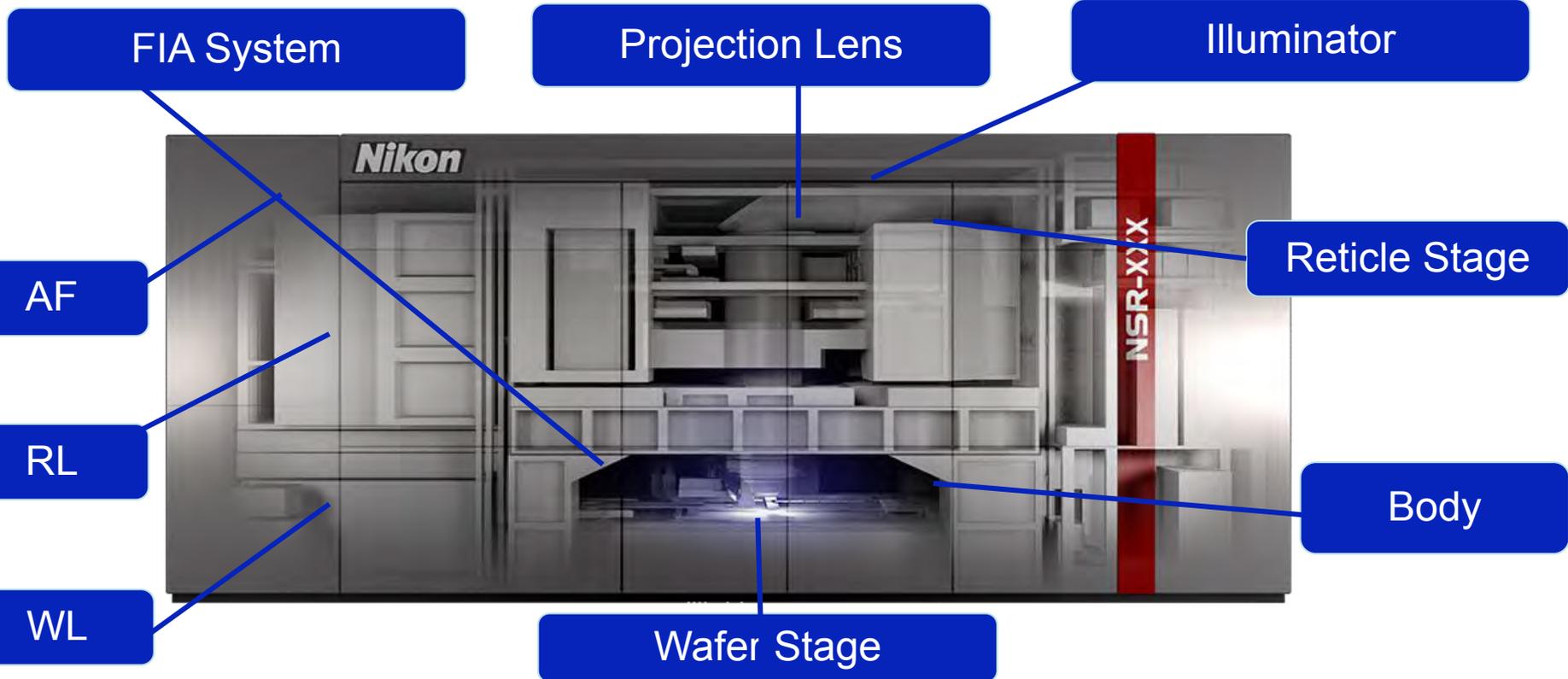


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Modular Overview



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- Enhanced overlay and throughput
- Improved AF stability/edge performance
- High-speed/precision technologies for larger wafers + improve total productivity

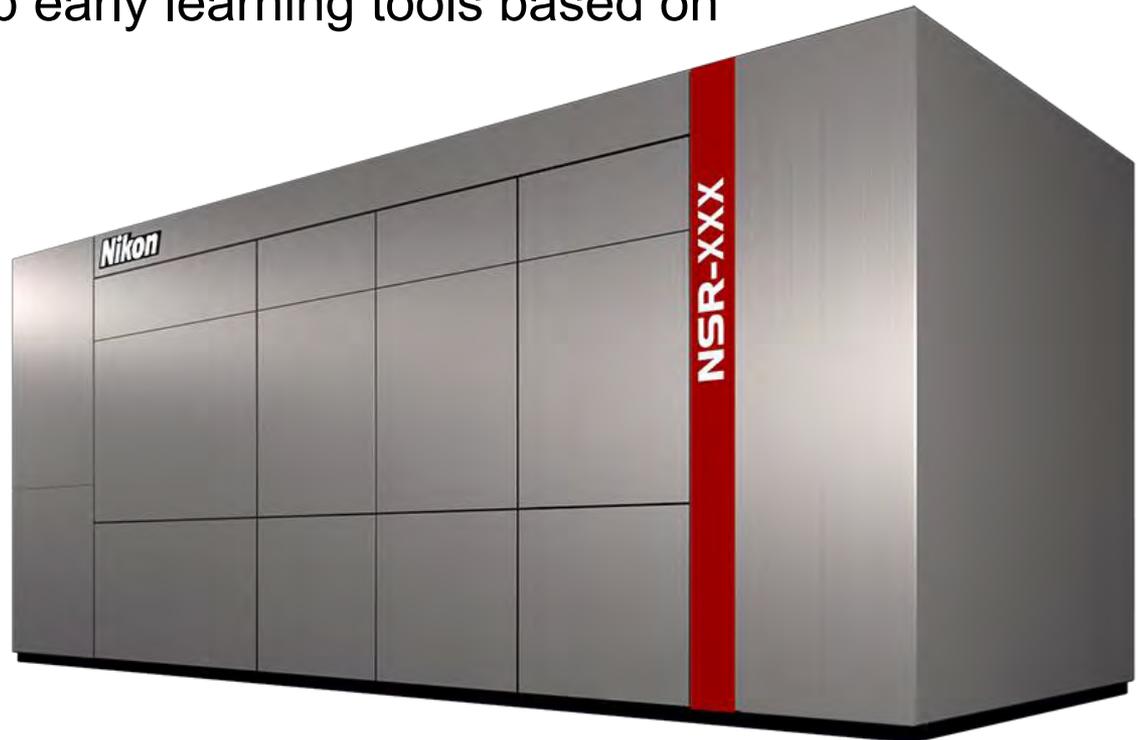
Opportunity to innovate in all modules

Nikon 450 mm Plans



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- Nikon will leverage our experience with the transition to 300 mm and our *Streamline* Platform
- By 2015, Nikon plans to ship early learning tools based on 193 nm immersion
- Nikon plans to ship 450 mm HVM tools in 2017 through our joint development effort with a chipmaker



Nikon is joining the Global 450 mm Consortium (G450C)

Concluding Remarks



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- **The need for 450 mm is driven by economic and productivity issues**
- **450 mm will mitigate increased costs due to lithography complexity for 193 nm immersion**
- **450 mm and EUV may prove to be a more difficult issue, especially in the sub-20 nm regime**
- **Nikon is building 450 mm systems based on the foundation of our proven *Streamline* Platform**
- **Nikon has joined the Global 450 Consortium**
 - We will be delivering a 450 mm learning tool by 2015
- **Nikon will be delivering HVM tools by 2017**



Thank You



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